



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

#15/B  
U.S. Patent  
Office  
MAR 11/03

In re Application of )  
Hans-Ulrich Krotil et al. )  
Serial No.: 09/869,789 ) Group:  
Filed: July 23, 2002 )  
Title: METHOD AND DEVICE FOR SIMULTANEOUSLY )  
DETERMINING THE ADHESION, FRICTION, AND )  
OTHER MATERIAL PROPERTIES OF A SAMPLE )

**PRELIMINARY AMENDMENT DELETING**  
**MULTIPLE DEPENDENT CLAIMS**

Assistant Commissioner of Patents  
Washington, DC 20231

Sir:

Prior to calculating the filing fee, please enter the following amendments to the application.

**IN THE CLAIMS**

Please amend claims 3, 5, 7, 9, 11, 13, 17, 19, 21, 23-25, and 27 as follows:

B1 3. Raster probe microscope according to claim 1,  
characterized by periodic raster-probe and/or sample oscillations.

B2 5. Raster probe microscope according to claim 3,  
characterized in that,  
the vertical oscillation of the raster probe (1) and/or of the sample (25) occurs with a first frequency of at least 10 Hz and a first amplitude of at least 1 nm.

B3 7. Raster probe microscope according to claim 5,  
characterized in that,  
the vertical oscillation of the raster probe (1) and/or of the sample (25) is additionally excited or modulated with a second frequency of at least 1 kHz and a second amplitude of at least 0.1 nm.

B4 9. Raster probe microscope according to claim 3,  
characterized in that,  
the sescond raster-probe and/or sample oscillation is a horizontal oscillation with a frequency of at least 500 Hz and an amplitude of at least 0.1 nm.

B5 11. Raster probe microscope according to claim 3,  
characterized by

TECHNOLOGY CENTER 2800  
MAR 14 2003  
RECEIVED